

Notice of References Cited

Application/Control No.

09/670,917

Applicant(s)/Patent Under

Reexamination

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Examiner

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Art Unit

2822

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	N	JP 06080962 A	03-1994	Japan	Mori et al.	252/79.3
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Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.